

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Atty. Docket No.

35.C5745 CIP/CII/DI

Application No.

08/474,324

Applicant

SEISHIRO YOSHIOKA ET AL.

Filing Date

June 7, 1995

Group

2211

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
J591	4 0 9 3 5 6 2	6/6/78	Kishimoto	252	511	
	4 3 2 5 0 8 4	4/13/82	Van Gorkon et al.	313	346	
	3 2 7 8 7 8 9	10/11/66	Shroff	313	346	
J591	3 7 3 5 1 8 6	5/23/73	Klopper et al.	313	346	

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation Yes No
J591	UK 2 0 6 0 9 9 1	5/17/81	United Kingdom			X
	SU 8 5 5 7 8 2	8/15/81	Soviet Union			Abstract Only
	DE 2 4 1 3 9 4 2	2/15/79	Germany			U.S. 3,998,678
	DE 1 8 0 0 9 5 2	7/22/71	Germany			Abstract Only
	DE 2 5 4 2 3 4 9	7/10/76	Germany			Abstract Only
	DE 2 0 1 2 1 0 1	3/6/78	Germany			U.S. 3,678,325
	DE 1 7 6 4 9 9 4	1/13/72	Germany			Abstract Only
	EP 0 0 7 3 0 3 1	3/2/83	Europe			Abstract Only
	GB 1 2 6 7 0 2 9	3/5/72	Great Britain			X
	GB 1 3 3 5 9 7 9	10/3/73	Great Britain			X
	JP 56 1 8 3 3 6	2/21/81	Japan			Abstract Only
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## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Page, Etc.)

J591	- M. Hartwell et al., "Strong Electron Emission From patterned Tin-indium Oxide Thin Films" Cambridge MA, pp. 519-521
	- M. Elinson et al., "The Emission of Hot Electrons And The Field Emissions Of Electrons From Tin Oxide", Radio Engineering and Electron Physics,

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J KNAPP

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5 Aug 96

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	3 6 6 3 8 5 7	5/16/72	A.M. Soellner et al.	313	339	

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						Yes	No
	44 - 2 6 1 2 5	1/4/69	Japan				
	46 - 2 0 9 4 9	6/12/71	Japan				
	44 - 2 7 8 5 2	11/18/44	Japan				
	46 - 3 8 0 6 0	11/9/71	Japan				
	45 - 3 1 6 1 5	10/13/70	Japan				
	44 - 2 7 8 5 3	11/18/69	Japan				
	44 - 2 8 0 0 9	11/19/69	Japan				
	46 - 2 4 4 5 6	7/14/71	Japan				
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OMB No. 0651-0011 (12/31/86)

<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)						Atty. Docket No. 35.C5745 CIP/CTI/DI		Application No. 08/474,324	
						Applicant SEISHIRO YOSHIOKA ET AL.			
						Filing Date June 7, 1995		Group 2211	

  

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JSK ↓ JSK	4 0 9 3 5 6 2	6/6/78	Kishimoto	252	511				
	4 3 2 5 0 8 4	4/13/82	Van Gorkon et al.	313	346				
	3 2 7 8 7 8 9	10/11/66	Shroff	313	346				
	3 7 3 5 1 8 6	5/23/73	Klopper et al.	313	346				

  

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	DE 1 7 6 4 9 9 4	1/13/72	Germany			Abstract Only			
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	GB 1 2 6 7 0 2 9	3/5/72	Great Britain			X			
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OMB No. 0651-0011 (12/31/86)

<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)						Atty. Docket No. 35,CS745 CTP/CII/DI		Application No. 08/474324	
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	44 - 3 2 2 4 7	12/23/69	Japan						
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